Notice of References Cited

Application/Control No.

10/002,915

Examiner

BRIAN P. YENKE

Applicant(s)/Patent Under
Reexamination
KIM ET AL.

Art Unit
Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
0.	Α.	US-2002/0027610	03-2002	Jiang et al.	348/448
	В	US-5,748,250	05-1998	Markandey et al.	348/451
	С	US-6,396,876	05-2002	Babonneau et al.	375/240.29
	D:	US-6,335,990	01-2002	Chen et al.	382/261
	Ε	US-5,532,750	07-1996	De Haan et al.	348/452
	F	US-6,681,054	01-2004	Gindele, Edward B.	382/272
	G	US-6,061,100	05-2000	Ward et al.	348/607
	Н	US-6,034,734	03-2000	De Haan et al.	348/458
X	1	US-5,943,099	08-1999	Kim, Young-taek	348/448
	J	US-5,903,680	05-1999	De Haan et al.	382/265
	К	US-5,694,177	12-1997	Flannaghan et al.	348/607
	L	US-5,682,205	10-1997	Sezan et al.	348/452
X	М	US-5,959,681	09-1999	Cho, Yong-Hun	348/452

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	P					
	ø					
	R					
	S					
	Τ					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

